

#### P-Channel Enhancement Mode MOSFET

### **Features**

# • -20V/-3.6A , $R_{\rm DS(ON)} = 70 {\rm m}\Omega({\rm typ.}) \ @ \ V_{\rm GS} = -4.5 {\rm V} \\ R_{\rm DS(ON)} = 100 {\rm m}\Omega({\rm typ.}) \ @ \ V_{\rm GS} = -2.5 {\rm V}$

- Super High Dense Cell Design
- Reliable and Rugged
- Lead Free Available (RoHS Compliant)

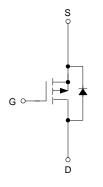
### **Applications**

 Power Management in Desktop Computer or DC/DC Converters

### **Pin Description**

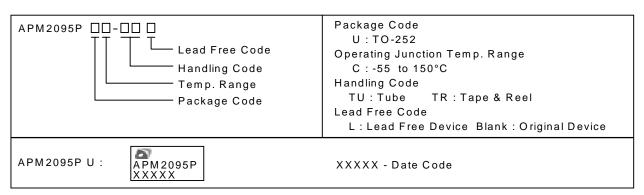


Top View of TO-252



P-Channel MOSFET

### **Ordering and Marking Information**



Note: ANPEC lead-free products contain molding compounds/die attach materials and 100% matte in plate termination finish; which are fully compliant with RoHS and compatible with both SnPb and lead-free soldiering operations. ANPEC lead-free products meet or exceed the lead-free requirements of IPC/JEDEC J STD-020C for MSL classification at lead-free peak reflow temperature.

ANPEC reserves the right to make changes to improve reliability or manufacturability without notice, and advise customers to obtain the latest version of relevant information to verify before placing orders.



# **Absolute Maximum Ratings**

Symbol	Parameter	Parameter			
Common Ratir	ngs (T <sub>A</sub> =25°C Unless Otherwise Noted)				
$V_{DSS}$	Drain-Source Voltage		-20		
$V_{GSS}$	Gate-Source Voltage		±10	V	
T <sub>J</sub>	Maximum Junction Temperature	Maximum Junction Temperature			
T <sub>STG</sub>	Storage Temperature Range		-55 to 150	°C	
Is	Diode Continuous Forward Current	T <sub>C</sub> =25°C	-12	А	
ounted on La	arge Heat Sink				
ı	200 va Dulaa Drain Current Teeted	T <sub>C</sub> =25°C	-20	۸	
l <sub>DP</sub>	300µs Pulse Drain Current Tested	T <sub>C</sub> =100°C	-12	Α	
- 1	Continuous Drain Courset	T <sub>C</sub> =25°C	-8	۸	
I <sub>D</sub>	Continuous Drain Current	T <sub>C</sub> =100°C	-5	Α	
Б		T <sub>C</sub> =25°C	50	147	
$P_{D}$	Maximum Power Dissipation	T <sub>C</sub> =100°C	20	W	
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Thermal Resistance-Junction to Case		°C/W	
lounted on Po	CB of 1in <sup>2</sup> Pad Area		•		
		T <sub>A</sub> =25°C	-20	^	
l <sub>DP</sub>	300µs Pulse Drain Current Tested	T <sub>A</sub> =100°C	-12	Α	
	Continue Borio Consul	T <sub>A</sub> =25°C	-4	^	
I <sub>D</sub>	Continuous Drain Current	T <sub>A</sub> =100°C	-3	Α	
		T <sub>A</sub> =25°C	2.5	147	
$P_{D}$	Maximum Power Dissipation	T <sub>A</sub> =100°C	1	W	
$R_{\theta JA}$	Thermal Resistance-Junction to Ambi	ent	50	°C/W	
lounted on Po	CB of Minimum Footprint				
		T <sub>A</sub> =25°C	-20	^	
l <sub>DP</sub>	300µs Pulse Drain Current Tested	T <sub>A</sub> =100°C	-12	Α	
ı	Court of Bridge and	T <sub>A</sub> =25°C	-3		
I <sub>D</sub>	Continuous Drain Current	T <sub>A</sub> =100°C	-2	Α	
		T <sub>A</sub> =25°C	1.6		
$P_D$	Maximum Power Dissipation	T <sub>A</sub> =100°C	0.6	W	
$R_{\theta JA}$	Thermal Resistance-Junction to Ambi	ent	75	°C/W	



# **Electrical Characteristics** (T<sub>A</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Toot Condition	APM2095PU			Unit	
Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Onit	
Static Ch	aracteristics			•	•		
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =-250μA	-20			V	
	Zoro Coto Voltago Proin Current V <sub>DS</sub> =-16V, V <sub>GS</sub> =0V			-1	^		
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	T <sub>J</sub> =85°C			-30	μΑ	
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{DS}=-250\mu A$	-0.5	-0.7	-1	V	
I <sub>GSS</sub>	Gate Leakage Current	V <sub>GS</sub> =±10V, V <sub>DS</sub> =0V			±100	nA	
D a	Drain-Source On-state Resistance	V <sub>GS</sub> =-4.5V, I <sub>DS</sub> =-3.6A		70	95		
R <sub>DS(ON)</sub> a	Dialii-Source Oil-state Resistance	V <sub>GS</sub> =-2.5V, I <sub>DS</sub> =-2A		100	125	mΩ	
Diode Ch	aracteristics						
V <sub>SD</sub> <sup>a</sup>	Diode Forward Voltage	I <sub>SD</sub> =-1A, V <sub>GS</sub> =0V		-0.7	-1.3	V	
Dynamic	Characteristics <sup>b</sup>						
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> =0V,V <sub>DS</sub> =0V,F=1MHz		12.5		Ω	
C <sub>iss</sub>	Input Capacitance	$V_{GS}=0V$ ,		500			
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =-15V,		170		pF	
C <sub>rss</sub>	Reverse Transfer Capacitance	Frequency=1.0MHz		120			
t <sub>d(ON)</sub>	Turn-on Delay Time			13	22		
T <sub>r</sub>	Turn-on Rise Time	$V_{DD}$ =-10V, $R_{L}$ =10 $\Omega$ , $I_{DS}$ =-1A, $V_{GEN}$ =-4.5V,		36	56	no	
t <sub>d(OFF)</sub>	Turn-off Delay Time	$R_{G}=6\Omega$		45	70	ns	
T <sub>f</sub>	Turn-off Fall Time	]		37	58		
Gate Cha	rge Characteristics <sup>b</sup>						
Qg	Total Gate Charge			11	15		
$Q_{gs}$	Gate-Source Charge	V <sub>DS</sub> =-10V, V <sub>GS</sub> =4.5V, I <sub>DS</sub> =-3.6A		2		nC	
$Q_{gd}$	Gate-Drain Charge	3.07		1.5			

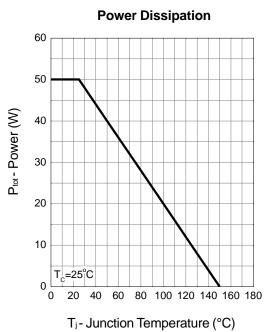
#### Notes:

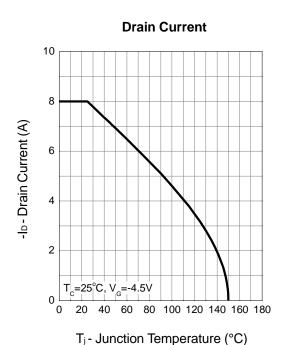
a : Pulse test ; pulse width≤300µs, duty cycle≤2%.

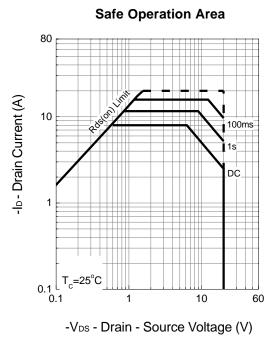
b : Guaranteed by design, not subject to production testing.



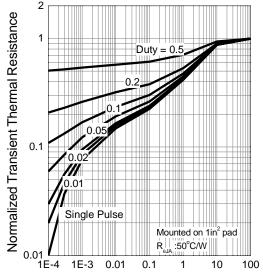
# **Typical Characteristics**







Thermal Transient Impedance

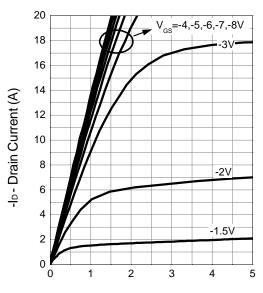


Square Wave Pulse Duration (sec)



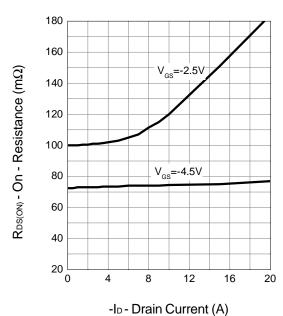
# **Typical Characteristics (Cont.)**

#### **Output Characteristics**

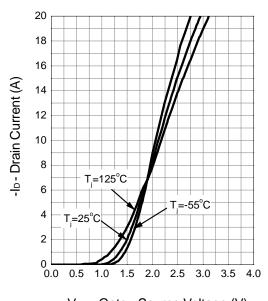


-VDS - Drain - Source Voltage (V)

#### **Drain-Source On Resistance**

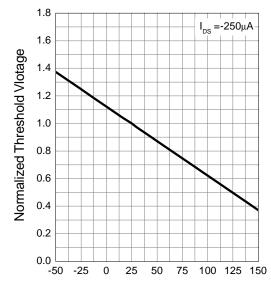


**Transfer Characteristics** 



-V<sub>GS</sub> - Gate - Source Voltage (V)

#### **Gate Threshold Voltage**

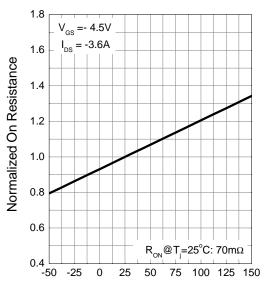


T<sub>j</sub> - Junction Temperature (°C)



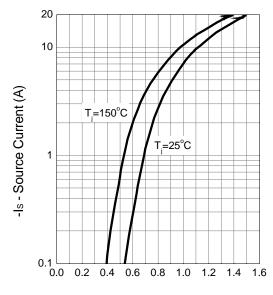
# **Typical Characteristics (Cont.)**

#### **Drain-Source On Resistance**



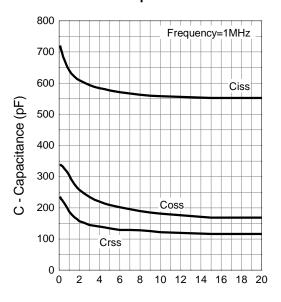
T<sub>j</sub>- Junction Temperature (°C)

#### **Source-Drain Diode Forward**



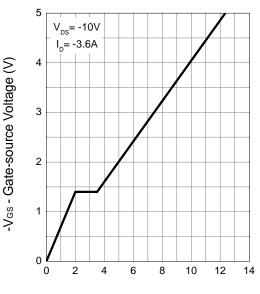
-V<sub>SD</sub> - Source - Drain Voltage (V)

#### Capacitance



-V<sub>DS</sub> - Drain - Source Voltage (V)

#### **Gate Charge**

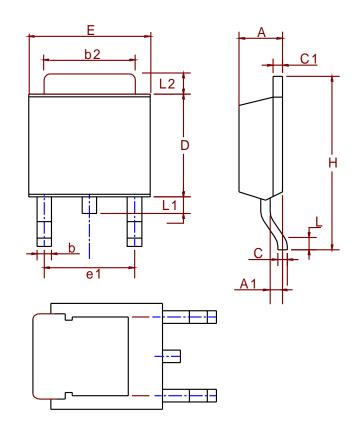


Q<sub>G</sub> - Gate Charge (nC)



# **Packaging Information**

TO-252( Reference JEDEC Registration TO-252)



Dim	Millim	neters	Inc	hes
Dim	Min.	Max.	Min.	Max.
А	2.18	2.39	0.086	0.094
A1	0.89	1.27	0.035	0.050
b	0.508	0.89	0.020	0.035
b2	5.207	5.461	0.205	0.215
С	0.46	0.58	0.018	0.023
C1	0.46	0.58	0.018	0.023
D	5.334	6.22	0.210	0.245
E	6.35	6.73	0.250	0.265
e1	3.96	5.18	0.156	0.204
Н	9.398	10.41	0.370	0.410
L	0.51		0.020	
L1	0.64	1.02	0.025	0.040
L2	0.89	2.032	0.035	0.080

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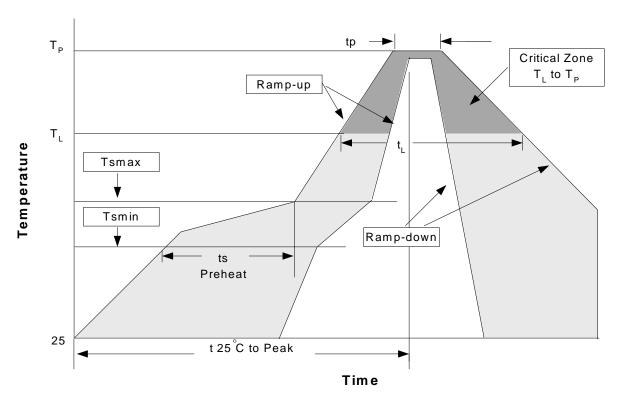
Rev. B.1 - Mar., 2005



# **Physical Specifications**

Terminal Material	Solder-Plated Copper (Solder Material : 90/10 or 63/37 SnPb), 100%Sn
Lead Solderability	Meets EIA Specification RSI86-91, ANSI/J-STD-002 Category 3.

### Reflow Condition (IR/Convection or VPR Reflow)



### **Classification Reflow Profiles**

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate $(T_L \text{ to } T_P)$	3°C/second max.	3°C/second max.
Preheat - Temperature Min (Tsmin) - Temperature Max (Tsmax) - Time (min to max) (ts)	100°C 150°C 60-120 seconds	150°C 200°C 60-180 seconds
Time maintained above: - Temperature (T <sub>L</sub> ) - Time (t <sub>L</sub> )	183°C 60-150 seconds	217°C 60-150 seconds
Peak/Classificatioon Temperature (Tp)	See table 1	See table 2
Time within 5°C of actual Peak Temperature (tp)	10-30 seconds	20-40 seconds
Ramp-down Rate	6°C/second max.	6°C/second max.
Time 25°C to Peak Temperature	6 minutes max.	8 minutes max.

Notes: All temperatures refer to topside of the package .Measured on the body surface.



# **Classification Reflow Profiles(Cont.)**

Table 1. SnPb Entectic Process - Package Peak Reflow Temperatures

Package Thickness	Volume mm³ <350	Volume mm³ ≥350
<2.5 mm	240 +0/-5°C	225 +0/-5°C
≥2.5 mm	225 +0/-5°C	225 +0/-5°C

Table 2. Pb-free Process – Package Classification Reflow Temperatures

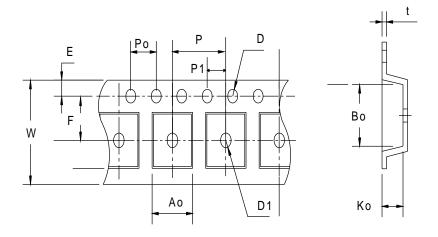
Package Thickness	Volume mm <sup>3</sup> <350	Volume mm <sup>3</sup> 350-2000	Volume mm³ >2000
<1.6 mm	260 +0°C*	260 +0°C*	260 +0°C*
1.6 mm – 2.5 mm	260 +0°C*	250 +0°C*	245 +0°C*
≥2.5 mm	250 +0°C*	245 +0°C*	245 +0°C*

<sup>\*</sup>Tolerance: The device manufacturer/supplier **shall** assure process compatibility up to and including the stated classification temperature (this means Peak reflow temperature +0°C. For example 260°C+0°C) at the rated MSL level.

### **Reliability Test Program**

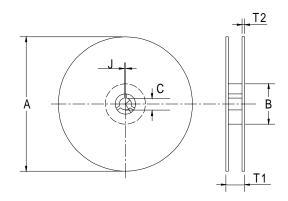
Test item	Method	Description
SOLDERABILITY	MIL-STD-883D-2003	245°C,5 SEC
HOLT	MIL-STD 883D-1005.7	1000 Hrs Bias @ 125°C
PCT	JESD-22-B, A102	168 Hrs, 100% RH, 121°C
TST	MIL-STD 883D-1011.9	-65°C ~ 150°C, 200 Cycles

### **Carrier Tape & Reel Dimensions**





# **Carrier Tape & Reel Dimensions (Cont.)**



Application	Α	В	С	J	T1	T2	W	Р	E
	330 ±3	100 ± 2	13 ± 0. 5	2 ± 0.5	16.4 + 0.3 -0.2	2.5± 0.5	16+ 0.3 - 0.1	8 ± 0.1	1.75± 0.1
TO-252	F	D	D1	Ро	P1	Ao	Во	Ko	t
	7.5 ± 0.1	1.5 +0.1	1.5± 0.25	4.0 ± 0.1	2.0 ± 0.1	6.8 ± 0.1	10.4± 0.1	2.5± 0.1	0.3±0.05

(mm)

### **Cover Tape Dimensions**

Application	Carrier Width	Cover Tape Width	Devices Per Reel
TO- 252	16	13.3	2500

### **Customer Service**

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